MOSFET – Power, N-Channel, SUPERFET[®] III, FRFET[®] 650 V, 40 A, 82 mΩ

NVHL082N65S3F

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III MOSFET is very suitable for the various power system for miniaturization and higher efficiency.

SUPERFET III FRFET MOSFET's optimized reverse recovery performance of body diode can remove additional component and improve system reliability.

Features

- 700 V @ T_J = 150°C
- Typ. $R_{DS(on)} = 64 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. $Q_g = 81 \text{ nC}$)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 722 pF)
- 100% Avalanche Tested
- AEC-Q101 Qualified and PPAP Capable

Applications

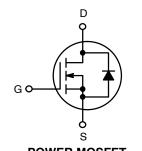
- Automotive On Board Charger HEV-EV
- Automotive DC/DC converter for HEV-EV



ON Semiconductor®

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V _{DSS}	R _{DS(ON)} MAX	I _D MAX
650 V	82 mΩ @ 10 V	40 A

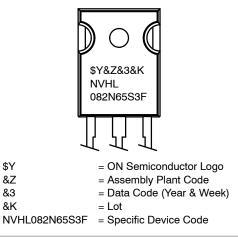






CASE 340CX

MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Paramet	Value	Unit V	
V _{DSS}	Drain to Source Voltage			
V _{GSS}	Gate to Source Voltage	– DC	±30	V
		– AC (f > 1 Hz)	±30	
Ι _D	Drain Current	– Continuous (T _C = 25°C)	40	А
		– Continuous (T _C = 100°C)	25.5	
I _{DM}	Drain Current	- Pulsed (Note 1)	100	А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)	510	mJ	
E _{AR}	Repetitive Avalanche Energy (Note 1)	3.13	mJ	
dv/dt	MOSFET dv/dt Peak Diode Recovery dv/dt (Note 3)		100	V/ns
			50	
PD	Power Dissipation	(T _C = 25°C)	313	W
		– Derate Above 25°C	2.5	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. $I_{AS} = 4.8 \text{ A}$, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. 3. $I_{SD} \leq 20 \text{ A}$, di/dt $\leq 200 \text{ A}/\mu$ s, $V_{DD} \leq 400 \text{ V}$, starting $T_J = 25^{\circ}C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	

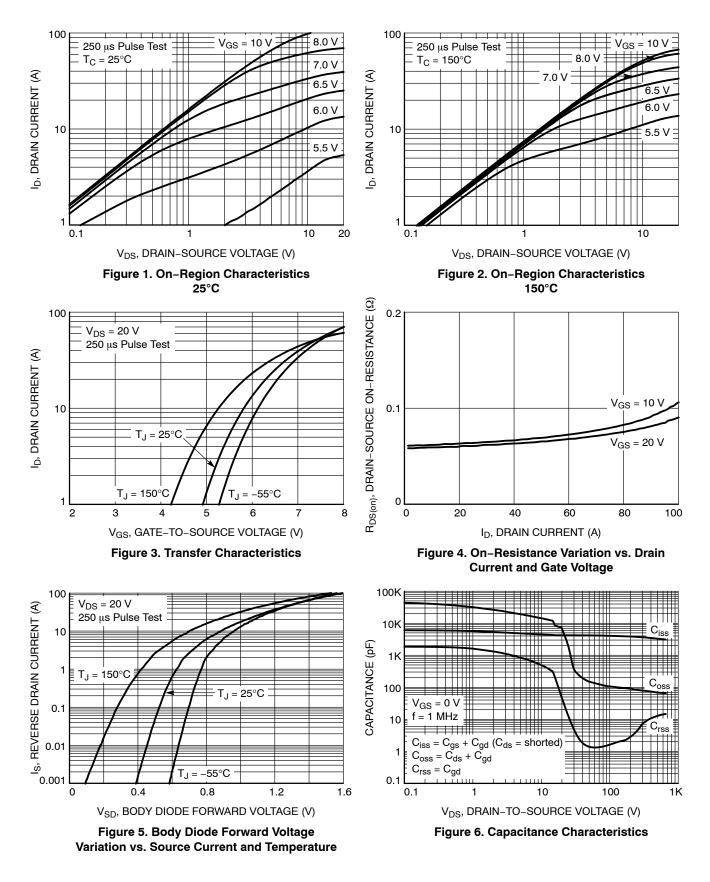
PACKAGE MARKING AND ORDERING INFORMATION

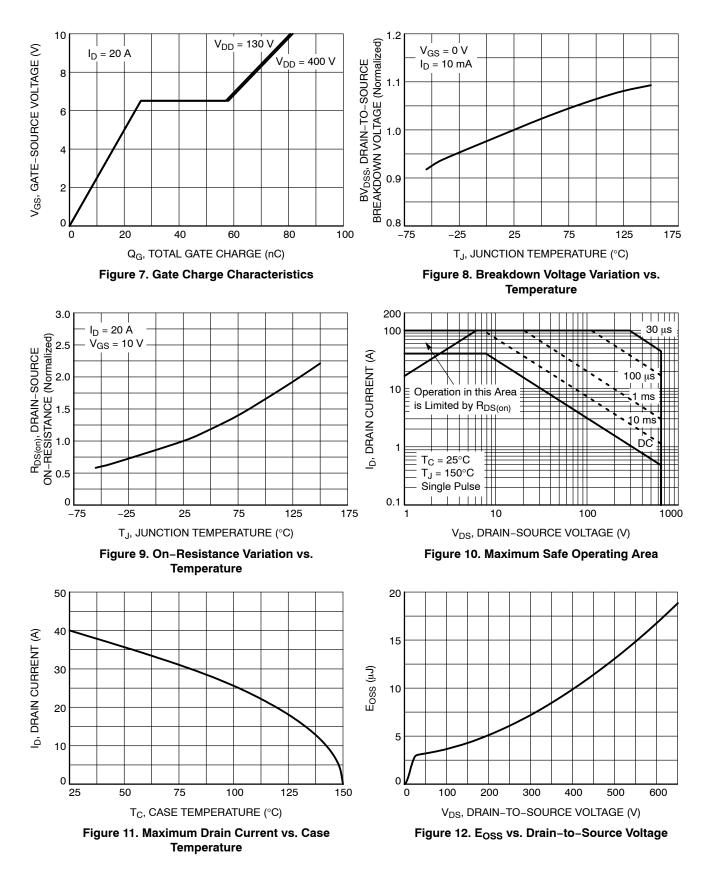
Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
NVHL082N65S3F	NVHL082N65S3F	TO-247	Tube	N/A	N/A	30 Units

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	V_{GS} = 0 V, I_D = 1 mA, T_J = 25°C	650	-	-	V
		V_{GS} = 0 V, I _D = 10 mA, T _J = 150°C	700	-	-	V
$\Delta \text{BV}_{\text{DSS}} / \Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 20 mA, Referenced to 25°C	-	0.7	_	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	10	μA
		V_{DS} = 520 V, T_{C} = 125°C	-	127	-	
I _{GSS}	Gate to Body Leakage Current	V_{GS} = ± 30 V, V_{DS} = 0 V	-	-	±100	nA
ON CHARACTE	RISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 1 \text{ mA}$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 20 A	-	64	82	mΩ
9 _{FS}	Forward Transconductance	V _{DS} = 20 V, I _D = 20 A	-	24	-	S
DYNAMIC CHA	RACTERISTICS	•				
C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V, f = 1 MHz	-	3410	-	pF
C _{oss}	Output Capacitance		-	70	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	722	-	pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	126	-	pF
Q _{g(tot)}	Total Gate Charge at 10 V	V _{DS} = 400 V, I _D = 20 A, V _{GS} = 10 V (Note 4)	-	81	-	nC
Q _{gs}	Gate to Source Gate Charge		-	24	-	nC
Q _{gd}	Gate to Drain "Miller" Charge		_	32	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	1.9	-	Ω
SWITCHING CH	IARACTERISTICS					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 20 \text{ A},$	-	31	-	ns
t _r	Turn-On Rise Time	V _{GS} = 10 V, R _g = 4.7 Ω (Note 4)	-	29	-	ns
t _{d(off)}	Turn-Off Delay Time		_	76	-	ns
t _f	Turn-Off Fall Time		_	16	-	ns
SOURCE-DRAII	N DIODE CHARACTERISTICS					
۱ _S	Maximum Continuous Source to Drain Diode Forward Current			-	40	Α
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current		-	-	100	А
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_{SD} = 20 A$	-	-	1.3	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 V, I_{SD} = 20 A,$	-	108	-	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt = 100 A/μs	-	410	-	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Essentially independent of operating temperature typical characteristics.





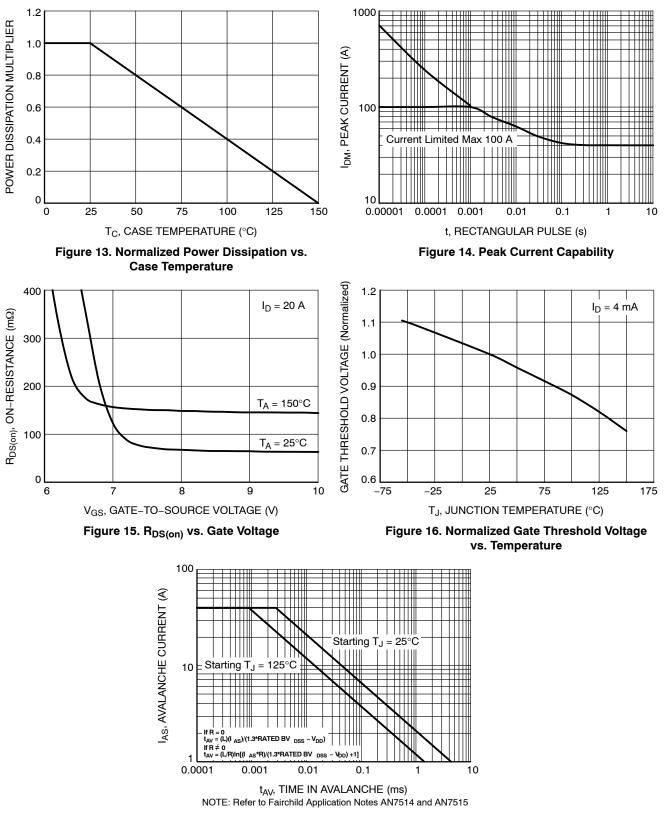


Figure 17. Unclamped Inductive Switching Capability

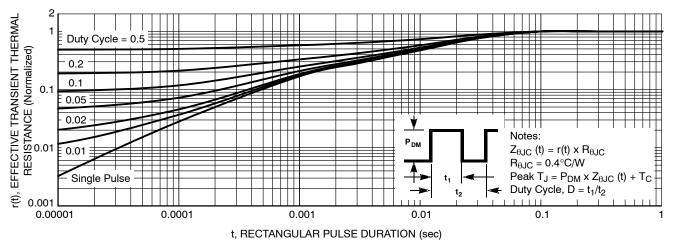
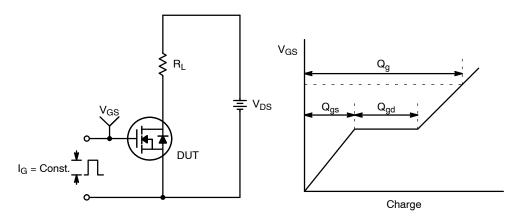


Figure 18. Transient Thermal Response





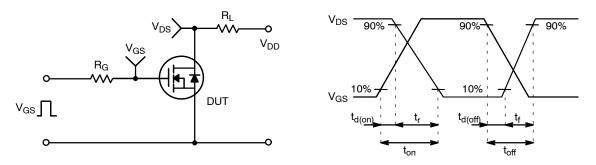
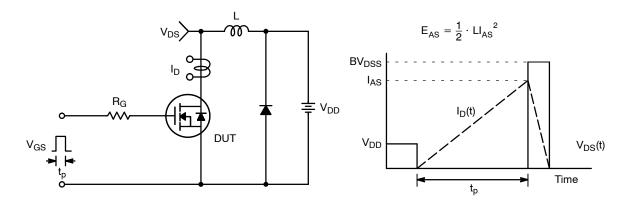


Figure 20. Resistive Switching Test Circuit & Waveforms





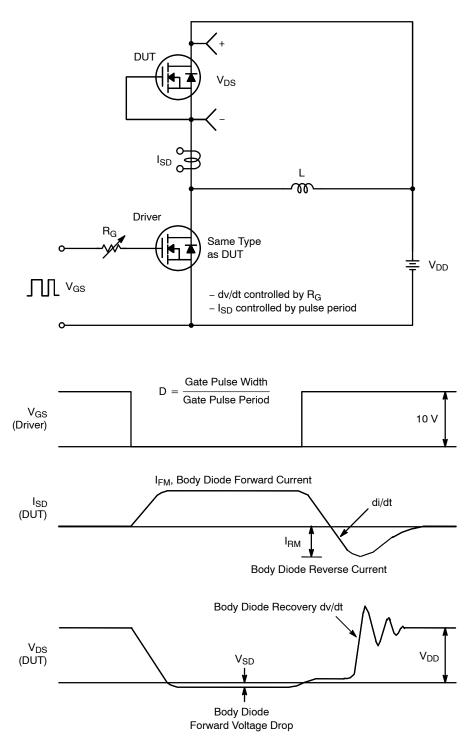
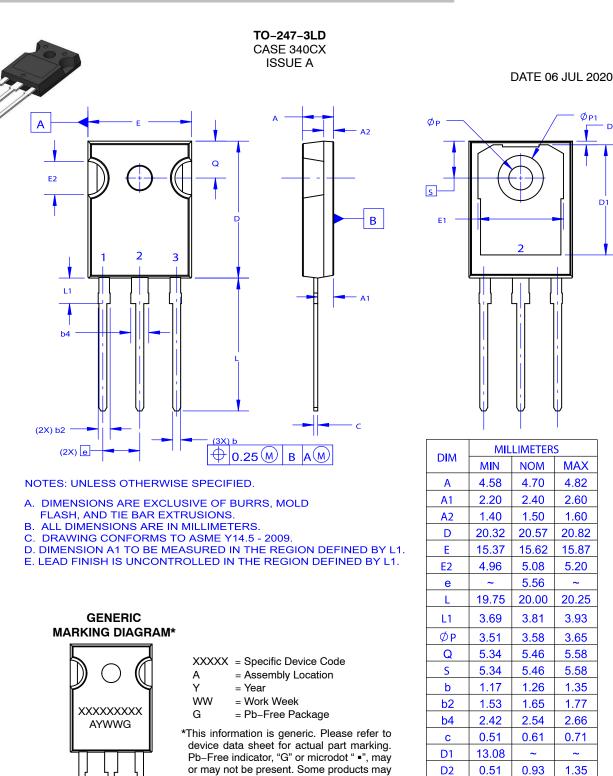


Figure 22. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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